

**Search Notes**

Application/Control No.

10/803,084

Examiner

Chuck Huynh

Applicant(s)/Patent under  
Reexamination

TAKAKI ET AL.

Art Unit

2617

**SEARCHED**

Class	Subclass	Date	Examiner
Updated	Search	6/6/2007	CH
455	418	6/6/2007	CH
455	456.4	6/6/2007	CH

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Class/Subclass	6/6/2007	CH
Combined Text Search	6/6/2007	CH